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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		<b>Complete if Known</b>	
		Application Number	10/707,227
		Filing Date	November 28, 2003
		First Named Inventor	Rafael NADAL GUARDIA
		Art Unit	2829
Sheet 1 of 1	Examiner Name	Nguyen, V	
		Attorney Docket Number	014442-000013

U.S. PATENT DOCUMENTS						
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)				

FOREIGN PATENT DOCUMENTS							
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>3</sup>
		Country Code <sup>2</sup> -Number <sup>2</sup> -Kind Code <sup>2</sup> (if known)					

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
VN	AA	Walker et al., "A Parallel Measurement System for the Extraction of Level 3 Spice Parameters", Proc. IEEE Int. Conf. On Microelectronic Test Structure, Edinburgh XP010000918, pg 135, left-hand column, lines 1-140. right-hand column. last line. Figure 1a. (March 1990).	

Examiner Signature		Date Considered	06/23/05
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional). 2 See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 If possible. 6 Applicant is to place a check mark here if English language Translation is attached.

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# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

Stylesheet Version v18.0

## Title of Invention

SEMICONDUCTOR DEVICE FOR DETECTING AND  
ADJUSTING A THRESHOLD VALUE VARIATION

Application Number :

10/707227

11/28/03

Confirmation Number:

First Named Applicant:

Rafael Nadal Guardia

Attorney Docket Number:

014442-13

Art Unit:

2829

Examiner:

Nguyen 7V

Search string:

( 6275972 or 5648920 or 5777518 ).pn

## US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
VN	1	6275972	2001-08-14	Long et al.			
VN	2	5648920	1997-07-15	Duvvury et al.			
VN	3	5777518	1998-07-07	Bailey			

## Signature

Examiner Name	Date
Mark Nguyen	06/23/05